## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | LIN ET AL. | Examiner | Art Unit | Brian R. Peugh | 2187 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,748,033	06-2004	Shiraishi et al.	375/340
*	В	US-6,704,848	03-2004	Song, Hwan-Seok	711/157
*	С	US-2004/0258170	12-2004	Lin et al.	375/260
*	D	US-6,151,690	11-2000	Peeters, Miguel	714/701
*	E	US-6,910,110	06-2005	Kim et al.	711/157
*	F	US-5,940,863	08-1999	Fimoff et al.	711/157
	G	US-			
	H	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	U\$-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	s					
	Т					

## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	w					
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